



# A Review on Nano Transistor Applications of Layered Dithioxotungsten

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## Abstract

Dithioxotungsten is chemically known as Tungsten disulfide ( $WS_2$ ) and is known for its superlubrication. In this review article, the performance of dithioxotungsten ( $WS_2$ ) as a channel material in nanotransistors is analysed based on the performance of  $WS_2$  on regard of mobility of charge carriers, on/off ratio of transistors, channel width to length ratio, channel thickness and, I-V characteristics and transistor performance.

**Key words:** Dithioxotungsten,  $WS_2$ , Nano Transistors

## 1. Introduction

Graphene as a two-dimensional material is having high mobility, but its non-bandgap nature limits the implementation of 2D geometry in certain areas such as transistors and sensors<sup>1</sup>. Transition Metal Dichalcogenides (TMDs) are one of the most adaptable materials due to their wide variety of physicochemical, electrical and mechanical properties that lie in between the semiconductor and metal<sup>2</sup>. Beyond TFTs, FETs are proposed as the high-performance devices. For the



fabrication of the field effect transistors (FETs) graphene can be used but, it is not a promising candidate as it lacks bandgap and can't be used as active channel. Although bandgap can be introduced and tuned by fabricating graphene in to nano ribbon form<sup>3</sup>, functionalization with different chemical elements<sup>4</sup>, using bilayer graphene<sup>5</sup> etc. But the complexity of fabrication and degradation of mobility is arising with serious questions about the device performance like drastic lowering of on/off ratio<sup>6</sup>. Two dimensional dichalcogenides is the best alternative candidates and these are better alternatives compared to graphene-based FETs because of its bandgap ranges from 1- 2 eV<sup>7</sup>. Among them Tungsten based dichalcogenide 2D materials show promising thickness dependent electronics band structure. These materials exhibit comparatively high carrier mobility<sup>8-9</sup>. Among the Tungsten based 2D dichalcogenides WS<sub>2</sub> shows the characteristic behaviour such as transition from indirect bandgap to direct band gap material when it is peeled down to mono layers<sup>10-11</sup>. WS<sub>2</sub> as bulk material shows an indirect bandgap of 1.4 eV and it's monolayer shows a direct bandgap of 2.1 eV<sup>12-13</sup>.

WS<sub>2</sub> is a layered transition metal dichalcogenide (TMDC)<sup>14-17</sup>. WS<sub>2</sub> exhibit high photoluminescence when exfoliated in bi/few layers<sup>14-17</sup>. The optical bandgap of WS<sub>2</sub> shows a change from indirect, 1.3 – 1.4 eV to direct, 1.8 – 2.1 eV in mono/ bi layers<sup>12-17</sup>. In direct bandgap structures the mobility and conductivity of charge carriers in WS<sub>2</sub> can be tuned by application of external field<sup>12-17</sup>. This property makes WS<sub>2</sub> a potential candidate to be applied in field effect thin film transistors. As the thickness of single layer WS<sub>2</sub> is of the order of 0.7 nm, exploring single/bi/few layers of WS<sub>2</sub> as channels in transistors for charge transport, great miniaturization of the device can be actualised<sup>17-19</sup>. Exploration of flexible nanotransistors is a trending field in semiconducting material research. The electrical properties of TMDCs vary from insulating to metallic behaviour based on transition metal d-electrons and crystal structures<sup>20-22</sup>. As tungsten is one of the most abundant elements in the earth's crust and also very dense and cost effective it is interesting to study the properties of WS<sub>2</sub>.

Among all TMDCs WS<sub>2</sub> shows more semiconducting behaviour for thin film transistor applications because of huge photoluminescence, direct bandgap, mechanical flexibility, chemical stability, large in-plane carrier mobility, high spin orbit coupling energy of about 420 MeV, large exciton binding energy and a high mobility of the order of 300 cm<sup>2</sup>/V-s<sup>23-26</sup>. Monolayer WS<sub>2</sub> is well studied for transistor applications due to excellent carrier mobility, as well as its potential applications in spintronics, valleytronics, energy-storage, sensing, electronic and photonic devices applications<sup>12-26</sup>. WS<sub>2</sub> is having many properties, like the transition



of indirect to direct bandgap, layer-dependent bandgap, large exciton binding energy, strong spin-orbit splitting, valley selection etc. and shows good stability at ambient conditions. It is exhibiting higher quantum efficiency, wider valence band maximum splitting and, lower effective mass of the carrier due to the presence of heavier tungsten atom<sup>12-26</sup>.

Influence of methods of preparation like mechanical exfoliation, liquid exfoliation, pulsed laser deposition, chemical vapour deposition, physical vapour deposition, e-beam evaporation etc., are found to alter the optoelectronic properties of WS<sub>2</sub><sup>27-35</sup>. The design of transistor, like the position of the gate terminal, which is classified into top contact and bottom contact structures are also affecting the performance of the transistors<sup>36-37</sup>. Due to the large injection area in top contact structures, the field effect mobility is found to be higher and contact resistance is lower<sup>36-37</sup>. But due to poor morphology in bottom contact structures the mobility is lower<sup>36-37</sup>. Top contact structures show good performance due to the reduced contact resistance at the source and drain electrodes<sup>36-37</sup>. The performance of TFT is also depending on the techniques of doping of the channel material, the choice of the substrates, the selection of contact materials and contact resistance<sup>36-37</sup>. An on/off ratio of 10<sup>5</sup> to 10<sup>7</sup> is reported in the case of WS<sub>2</sub> in various deposition conditions of the channel material and design of TFT, with a mobility of 13 to 489 cm/V-s<sup>6, 38-39</sup>.

In this review article, the performance of dithioxotungsten (WS<sub>2</sub>) as a channel material in nano transistors is analysed based on the performance of WS<sub>2</sub> on regard of mobility of charge carriers, on/off ratio of transistors, channel width to length ratio, channel thickness and, I-V characteristics and transistor performance.

### WS<sub>2</sub> – Analysis as a versatile optoelectronic material

Dithioxotungsten consists of S-W-S sandwich pattern, as shown in figure 1, of atoms arranged in a trigonal prismatic configuration [40]. The crystal lattice of 2-H WS<sub>2</sub> belongs to the non-symmorphic hexagonal space group P6<sub>3</sub>/mmc (D<sub>6h</sub>) which has the space inversion symmetry<sup>41-42</sup>. Single layer has 1H structure<sup>41</sup>. Monolayer WS<sub>2</sub> belongs to P<sub>6</sub>m<sub>2</sub>(D<sub>3h</sub>) group<sup>41</sup>. Even layer WS<sub>2</sub> has the space inversion symmetry while odd layer WS<sub>2</sub> lacks the space inversion symmetry<sup>41</sup>. The conduction band minimum (CBM) and the valance band maximum (VBM) are both located at K point in monolayer WS<sub>2</sub>. When the layer number of WS<sub>2</sub> increases, the VBM shifts to Γ point, while the CBM locates between K and Γ points (called Q point) [41]. The band edge states at K point have dominant contributions from the tungsten d(x<sub>2</sub>-y<sub>2</sub>), d<sub>xy</sub>, and d<sub>z</sub><sup>2</sup> orbitals with an admixture of the S p-orbitals<sup>41</sup>. For the states at Q<sub>c</sub> and Γ<sub>v</sub>, the contribution from the S p<sub>z</sub> orbitals become significant,



which plays an important role for the transition from direct to indirect bandgap from monolayer to bilayer and multilayer<sup>41</sup>.

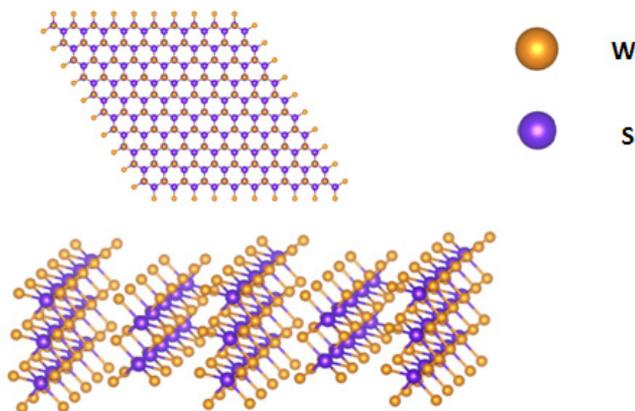


Figure 1: S-W-S pattern of  $WS_2$

The transition from a direct bandgap (monolayer  $WS_2$ ) to an indirect bandgap (bilayer and multilayer  $WS_2$ ) is a consequence of the spin-orbit coupling (SOC) and interlayer hopping<sup>41-43</sup>. Greater SOC in  $WS_2$  results in spin-orbit splitting of the valence band of the order of 400 meV near the valence K point<sup>41-43</sup>. Tungsten  $d_{xy}$  and  $d_{(x-y)^2}$  orbitals are highly localized in individual layers, due to this, VB splitting near the K point is dominated. The spin-orbit splitting energy has not much changes with the number of layers in the sample, as interlayer hopping of orbitals is comparatively lower<sup>41</sup>. In the case of monolayer  $WS_2$  samples, splitting of the VBM can be associated with the lack of inversion symmetry and also the spin-orbit effect. But the corresponding splitting in the case of bilayer is due to the combination of interlayer interaction and SOC.

Due to the large SOC, the VBM of monolayer  $WS_2$  exhibit the spin-index locked with the valley- index. The VBM valley K or -K has only the spin up or down electrons respectively. This leads to the valley-dependent optical selection rules. As per the selection rule, the circularly polarized light can selectively excite the K or -K valley electrons from the spin-polarized bands. The interlayer hopping energy in  $WS_2$  is of the order of 0.1 eV, which is lesser than the spin-valley coupling strength in  $WS_2$  which is of the order of 0.4 eV<sup>41</sup>.

Exciton in  $WS_2$  is highly confined to the plane of the ML. With change in



dielectric atmosphere, both the electron and hole experience a reduced screening effect. Hence the bandgap is expected to increase for monolayer  $WS_2$  (2.7 eV). With the exciton binding energy (0.7 eV), an enhanced electron–hole interaction can be expected<sup>42</sup>.

Raman scattering is a very good tool for confirmation of formation of  $WS_2$ . The major vibrational modes of  $WS_2$  can be analysed with Raman scattering experiment. Longitudinal Acoustic (M) at  $176\text{ cm}^{-1}$ , Doubly degenerated  $E_{2g}$  mode at  $356\text{ cm}^{-1}$ , 2LA(M) mode at  $352\text{ cm}^{-1}$  and singly degenerate  $A_g^1$  at  $418\text{ cm}^{-1}$  are major vibrational modes of  $WS_2$ . There will be shift in the peak position, appearance of shoulder peaks and change in the intensity of peaks depending on the number of layers in the sample, defects in the material, adsorption etc. Peak separation gives information about number of layers, deformation/splitting in peak gives information about strain/defects/adsorption in material<sup>44-46</sup>.

Synthesis methods of  $WS_2$  mono/few layers include methods like mechanical exfoliation – peeling/ scotch tape method, chemical vapor deposition, sputtering, atomic layer deposition, liquid phase exfoliation – laser ablation, ultrasonic method, molecular beam epitaxy, spin coating – on different substrates like titanium-titanium dioxide, graphite, silicon-silicon dioxide, graphene oxides, gold foil, h-boron nitride, sapphire etc. Chemical vapour deposition, especially the epitaxial one, has added advantages. In the samples grown through epitaxial method, the defect density is lower. Its possible to develop large area samples through this method. The electrical conductivity of CVD grown samples exhibit more endurance in-plane level<sup>27-35</sup>.

To achieve definite applicability, growth techniques need to control more finely, the size, layer thickness/ numbers, edge sharpness, the phase purity of the grown crystals and defects that may arise in the sample during growth process. Growth techniques influences the edge structure of the grown  $WS_2$ , ie., whether the sample edge is metal or chalcogen. This influences the carrier density distribution in and near the fermi energy level. It also affects how much the atomic orbitals overlap<sup>41</sup>. Profile of band-edge can be modified while growth using various band-structure engineering mechanisms. Bandgap can be modified by keen control of composition of alloy during synthesis<sup>41</sup>. In the case of heterostructures with no common species or dissimilar band profiles or with different lattice patterns, quantum engineering can be adopted for bandgap modification<sup>41</sup>. Combinations of different morphologies of lateral-vertical heterostructures can be developed, to contribute to the active channel layer of nanotransistors<sup>41</sup>.



### 3. WS<sub>2</sub> – Application as a channel material in Transistors

Field effect transistors based on WS<sub>2</sub> as channel layer show a large on/off ratio of greater than 10<sup>5</sup>. Large bandgap of two dimensional WS<sub>2</sub> can cause large on/off ratio<sup>47</sup>. Theoretically, the mobility of carrier in WS<sub>2</sub> channel could be high, the practically measured mobility is relatively low. Many factors like, the dielectric environment, percentage and type of defects and influence of adsorbents, can influence the performance of WS<sub>2</sub> as a channel material in transistors. The transport properties are highly influenced by number of layers and kind of stacking<sup>48</sup>. Process of adsorption when exposed to atmosphere is also influencing the performance of WS<sub>2</sub> channels. Hydrogen, water molecules and oxygen when get adsorbed to the surface of WS<sub>2</sub> cause p- type doping<sup>49-51</sup>. It has both advantage or disadvantage, as WS<sub>2</sub> can be used as an ambipolar material, at the same time, when mono/few layer TFT is exposed in air may exhibit weak p-type or n-type behavior<sup>49-51</sup>. Conductivity type can be modified from n-type to p-type in high pressure atmosphere of adsorbates<sup>49-51</sup>.

A schematic diagram of basic TFT architecture is shown in figure2, in which substrate can be solid substrates like silicon and flexible substrates like polyamide. Saptarshi Das et.al<sup>52</sup> successfully fabricated monolayered WS<sub>2</sub> on silicon (P++ Si) substrate with back gate architecture. Thermally grown SiO<sub>2</sub> of 100 nm over Si is served as the dielectric/insulating layer. A CVD grown WS<sub>2</sub> on titanium (Ti) substrate which was transferred through PMMA transfer technique in which initially PMMA will be coated over WS<sub>2</sub>- Ti substrate, then the entire substrate will be submerged in 1M NaOH until monolayer and PMMA fill get detached and remain in the solution, fully separated from Ti substrate. Then the entire PMMA with 2D WS<sub>2</sub> material was transferred on the Si/SiO<sub>2</sub> substrate. Then 40-50 nm Ni/Au source drain contacts made through e-beam lithography. Other architecture on flexible substrate include Polyamide, has been demonstrated by Thomas. N. Jackson et.al [53]. In their work a 100 nm Ti gate electrode array was deposited by sputtering and it was patterned photolithographically on polyamide substrate, and followed by a lift off process. A Plasma Enhanced Atomic layer deposition (PEALD) of Al<sub>2</sub>O<sub>3</sub> is then carried out at 200 °C as the gate dielectric / insulator layer for the device. A few layers of WS<sub>2</sub> 2D material is then transferred from Si substrate to patterned polyamide substrate by using PMMA transferring technique. A 50 nm Au source-drain contacts made by thermal evaporation and followed by photolithography procedure. A 30 nm Al<sub>2</sub>O<sub>3</sub> is then deposited over the device by ALD technique to encapsulate the device. Britnell et. al<sup>54</sup> also fabricated field effect tunnelling transistor with a more complex 2D



heterostructure, with entire stack with layered materials on flexible transparent substrates.

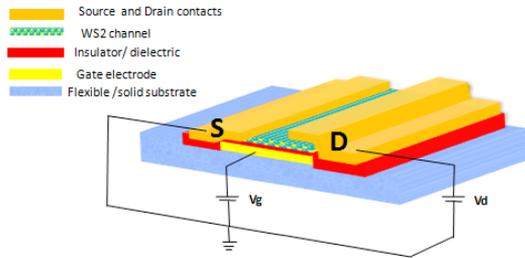


Figure 2: Schematic diagram of basic TFT architecture with  $WS_2$  channel

Effect of number of layers of  $WS_2$  on the performance of TFT is tabulated in table 1. In bilayer morphology, carrier mobility in  $WS_2$  TFT is  $300 \text{ cm}^2/\text{V-s}$  according to Palummo et. al<sup>55</sup>, which is greater than that of  $140 \text{ cm}^2/\text{V-s}$  monolayer channel (Nayak et. al)<sup>56</sup>

Table1. Effect of number of layers of  $WS_2$  in channel of TFT

Layers	Type	Band gap energy eV	Photoluminescence	Mobility ( $\text{cm}^2/\text{Vs}$ )	Carrier concentration	Ref.
Bulk $WS_2$	Indirect	1.3 - 1.4	Absent	255	n - type	Lan et al. <sup>41</sup>
Bilayer $WS_2$	Direct	1.800	Strong	300	p - type or n - type	Lu qet al. <sup>55</sup>
Monolayer $WS_2$	Direct	2.1	Less	140	n - type	Nayak. et al. <sup>56</sup>

Growth techniques influence the performance of TFT in many aspects. So, bandgap engineering, quantum engineering, phase pure growth, large area growth, single layer growth etc. plays greater role in the performance of TFT. Metal edge or chalcogen edge, sulphur vacancy etc. alters the mobility of carrier. Hwang et. al has reported an on/off ratio of  $10^5$  on scotch -tape peeled  $WS_2$  layer<sup>57</sup>. Jiang et. al<sup>58</sup> reports nitrogen plasma treatment to reduce sulphur vacancy caused deficiency. Treating with nitrogen plasma enhanced the mobility from 29.7 to  $184.2 \text{ cm}^2/\text{V-s}$



and on-off ratio from  $10^3$  to  $10^6$ . TFT on nitrogen plasma treatment result in ohm-like contact and exhibit linear  $I_{DS}-V_{DS}$  pattern near 0 V. S vacancies may result in reduced charge scattering. Nitrogen doping may result in reduced effective carrier mass and enhanced mobility<sup>57-58</sup>. Effect of growth techniques is tabulated in table 2<sup>57-63</sup>. A large on-off ratio of  $10^7$  is reported on a h-BN substrate grown through CVD method by Illarionov et al. A large mobility of  $486 \text{ cm}^2/\text{V}\cdot\text{s}$  in the same structure at 5 K is also reported<sup>57-63</sup>.

Table 2. Effect of growth techniques of  $\text{WS}_2$  on mobility and on-off ratio

Method	Substrate	Characteristics	Ohmic Contact	Mobility [ $\text{cm}^2/\text{Vs}$ ]	On/Off Current Ratio	Ref.
Scotch tape method	$\text{SiO}_2$	Clean	Ti / Al	30	$10^5$	Hwanget <i>al.</i> <sup>57</sup>
Fast pulsed I-V method	Si / $\text{SiO}_2$	Temperature instability	Ni / Al	44	$10^6$	Iqbalet <i>al.</i> <sup>58</sup>
Liquid phase exfoliation		Simplest cost effective, high deposition rate, purity, low capital cost material.			$10^6$	Ott <i>et al.</i> <sup>59</sup>
CVD	$\text{SiO}_2$	High performance. Large area production	$\text{SiO}_2$	80	$10^6$	Wuet <i>al.</i> <sup>60</sup>
CVD	h-BN	High uniformity. Hysteresis absent	Al / Au	185 at room temp. 486 at 5 K	$10^7$	Illarionov <i>et al.</i>
Mechanical exfoliation	h-BN	Low yield, low scattering impurities. Small size, high quality	Al	0.30	$4.56 \times 10^6$	Kumaret <i>al.</i>
E beam evaporation	$\text{SiO}_2$	Better stability and electrical performance	Ni	27.90	$10^6$	Wu <i>et al.</i>
HPHA	Si / $\text{SiO}_2$	Low contact resistance	Ti / Au	13.00	$10^5$	Yang <i>et al.</i>



Chemical functionalization with thiol also increases the carrier mobility, the low temperature mobility is reported to increase from 140 to 337  $\text{cm}^2/\text{V}\cdot\text{s}$ <sup>64</sup> and the ambient temperature mobility from 49 to 83  $\text{cm}^2/\text{V}\cdot\text{s}$ <sup>64</sup>. The device mobility can also be limited due to defect states in  $\text{SiO}_2$  layer in the substrate as it leads to the localization of charge carriers<sup>64</sup>. Hexagonal boron nitride could be a better alternative to avoid such defects and localization of charges. It is having atomically planar surface, high bandgap and low charge impurity density according to Iqbal et. Al<sup>65</sup>.

Contact materials also influences the performance of TFTs. The nature of contact materials determines the amount of charge injection and collection between the  $\text{WS}_2$  channel and the electrodes. An ohmic contact is more ideal for transistors, but it is very difficult to realize this in single/ bilayer channel materials<sup>66</sup>. The Fermi level pinning caused by interfacial states, results in mismatch of work function between the channel material and the electrode material. To reduce the contact problems, various techniques like annealing, doping, using metal interface layers, using graphene-based electrodes, using edge contacts etc. are being reported by various groups<sup>67</sup>.

Length to width ratio of the channel is a very important parameter which influences the performance of TFT. For a channel width of less than 100 nm, the threshold voltage was reported to increase suddenly with abrupt decrease in on-current. Channel size highly determines the hysteresis behaviour. Performance of TFT is dependent on the channel thickness and in the case of  $\text{WS}_2$  peak performance is reported in thickness range 6 -10 nm<sup>68</sup>.

The design of TFT itself is a deciding parameter in the performance of TFT whether it is top gated or bottom gated. Figure.3 demonstrates the schematic diagram of general design of top gated  $\text{WS}_2$  FET architecture. In this a high quality of thermally grown polished surface of  $\text{SiO}_2$  on Si substrate is represented for basic top gate architecture using  $\text{WS}_2$  monolayer as channel in FET. Electron beam lithography patterned source and drain contacts can be made through deposition of Cr/Au or Ti/Au in which Cr can be of 5 nm for the better adhesion and, Au or Ti can be of 50 nm thickness. Contact deposition can be preferably done by thermalevaporation method or else by sputter deposition method. For  $\text{WS}_2$  FETs, Cr/Au and Ti/Au contacts basically show ambipolarity in nature through which both P-type and n-type injection is possible. For P-type source and drain contacts high work function materials such as platinum can be deposited of thickness about



40-50 nm and a 50-60 nm thick Au can be deposited over Pt as the contact pad extension purposes.

Also, it has been reported that Ni/Au contacts of 40, 50 nm respectively deposited in the case of  $WS_2$  FETs on sapphire substrate in back gate architecture<sup>69</sup>. There are reports which mention annealing of contacts under Argon/  $H_2$  flow for the improvement of better contact resistance<sup>69-70</sup>. Gate electrodes can be fabricated with electron beam lithographically patterned and then  $Al_2O_3$  of 15 -30 nm can be deposited with Atomic Layer deposition Technique (ALD), and then Au of 50-60 nm again deposited over the dielectric material. Tae Wan Kim et.al<sup>71</sup> fabricated a similar architecture but with ion top gate over  $WS_2$  film FET. There are other different gate dielectric materials already reported with the 30 nm of  $HfO_2$ , 30nm  $SiO_2$ , 20 nm of h-BN (hexagonal boron Nitride) and then Au of 50-60 nm over the dielectric layer<sup>38</sup>.

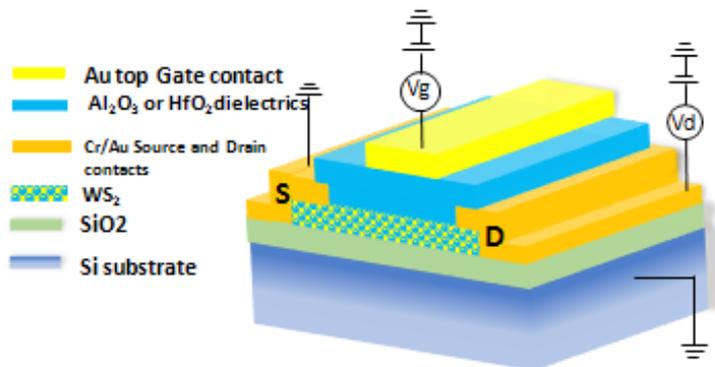


Figure 3: Top gate  $WS_2$  architecture

Figure 4 demonstrates the general bottom gate FET architecture. Bottom gate architecture of  $WS_2$  FETs can be fabricated with both highly doped n or p silicon substrates ( $n^{++}/P^{++}$  Si). A high quality thermally grown  $SiO_2$  can be deposited over the Si substrates and then the source and drain contacts can be made with above mentioned n-type or p-type contacts or ambipolar contacts. Bottom side of the substrate will act as common gate for the device. A dielectric gate material of



hexagonal boron nitride h-BN over Si/SiO<sub>2</sub> and WS<sub>2</sub> is transferred over these thin layered h-BN and source-drain contact can made through e-beam lithography with Al/Au contacts. h-BN is used as the gate material in back gate WS<sub>2</sub>FET architecture is also reported<sup>65, 72</sup>. A complex vertical heterostructure like, WS<sub>2</sub>-SnS<sub>2</sub> is reported in tunnelling field effect transistors with back gate architecture<sup>73</sup>. Table 3 shows the advantages of different designs of WS<sub>2</sub> based TFT structures<sup>63,74-76</sup>.

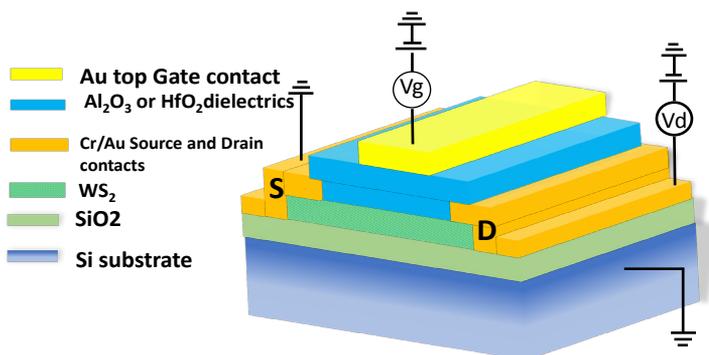


Figure 4: Bottom gate WS<sub>2</sub> transistor architecture

Table 3. Advantages of Bottom/ Top contact designs of TFT

Bottom Contact Structure	Top Contact Structure	Reference
Channel resistance decreases with channel length	Channel resistance increases with channel length	Mittal <i>et al.</i> <sup>74</sup>
Mobility is less	Elevated saturation mobility	Abuzaidet <i>et al.</i> <sup>75</sup>
High morphological disorder	Low morphological disorder	Mittal <i>et al.</i> <sup>74</sup>
Low drain current	High drain current	Yang <i>et al.</i> <sup>63</sup>
Low transconductance	High transconductance	Yeh <i>et al.</i> <sup>76</sup>



## Conclusion

Dithioxotungsten chemically known as Tungsten disulphide ( $WS_2$ ) is very good channel material to be applied in field effect transistors with high carrier mobility of upto  $486 \text{ cm}^2 / \text{V-s}$  at 5 K in bilayer thickness. In mono/bilayers it is a direct bandgap material with ample photoluminescence to be applied in optoelectronic devices. In this review article the performance of dithioxotungsten ( $WS_2$ ) as a channel material in nano transistors is analysed based on the performance of  $WS_2$  on regard of mobility of charge carriers, on/off ratio of transistors, channel width to length ratio, channel thickness and I-V characteristics. The material property of  $WS_2$ , like the space group to which  $WS_2$  belongs to, spin-orbit coupling in  $WS_2$ , Excitonic nature in  $WS_2$ , Raman vibrational modes, etc. which demonstrates  $WS_2$  as most adaptable transition dichalcogenide is also discussed. General top-gated and bottom-gated design for fabrication of  $WS_2$  channel transistor is also demonstrated.

## References

1. Tiwari, S. K., Sahoo, S., Wang, N., & Huczko, A. (2020). Graphene research and their outputs: Status and prospect. In *Journal of Science: Advanced Materials and Devices* (Vol. 5, Issue 1). <https://doi.org/10.1016/j.jsamd.2020.01.006>
2. Chen, X., Liu, C., & Mao, S. (2020). Environmental Analysis with 2D Transition-Metal Dichalcogenide-Based Field-Effect Transistors. In *Nano-Micro Letters* (Vol. 12, Issue 1). <https://doi.org/10.1007/s40820-020-00438-w>
3. Han, M. Y., Özyilmaz, B., Zhang, Y., & Kim, P. (2007). Energy band-gap engineering of graphene nanoribbons. *Physical Review Letters*, 98(20). <https://doi.org/10.1103/PhysRevLett.98.206805>
4. Samuels, A. J., & Carey, J. D. (2013). Molecular doping and band-gap opening of bilayer graphene. *ACS Nano*, 7(3). <https://doi.org/10.1021/nn400340q>
5. Oostinga, J. B., Heersche, H. B., Liu, X., Morpurgo, A. F., & Vandersypen, L. M. K. (2008). Gate-induced insulating state in bilayer graphene devices. *Nature Materials*, 7(2). <https://doi.org/10.1038/nmat2082>
6. Lin, X., Wang, F., Shan, X., Miao, Y., Chen, X., Yan, M., Zhang, L., Liu, K., Luo, J., & Zhang, K. (2021). High-performance photodetector and its optoelectronic mechanism of  $MoS_2/WS_2$  vertical heterostructure. *Applied Surface Science*, 546. <https://doi.org/10.1016/j.apsusc.2021.149074>
7. Krishnamurthi, S., & Brocks, G. (2021). 1D metallic states at 2D transition metal dichalcogenide semiconductor heterojunctions. *Npj 2D Materials and Applications*, 5(1). <https://doi.org/10.1038/s41699-021-00224-1>
8. Stewart, K. A., & Wager, J. F. (2016). Thin-film transistor mobility limits considerations. *Journal of the Society for Information Display*, 24(6). <https://doi.org/10.1002/jsid.452>



9. Li, H., Yin, Z., He, Q., Li, H., Huang, X., Lu, G., Fam, D. W. H., Tok, A. I. Y., Zhang, Q., & Zhang, H. (2012). Layered Nanomaterials: Fabrication of Single- and Multilayer MoS<sub>2</sub> Film-Based Field-Effect Transistors for Sensing NO at Room Temperature (Small 1/2012). *Small*, 8(1). <https://doi.org/10.1002/sml.201290004>
10. Zheng, J., Li, E., Ma, D., Cui, Z., Peng, T., & Wang, X. (2019). Effect on Schottky Barrier of Graphene/WS<sub>2</sub> Heterostructure With Vertical Electric Field and Biaxial Strain. *Physica Status Solidi (B) Basic Research*, 256(10). <https://doi.org/10.1002/pssb.201900161>
11. Horri, A., Faez, R., Pourfath, M., & Darvish, G. (2017). A computational study of vertical tunneling transistors based on graphene-WS<sub>2</sub> heterostructure. *Journal of Applied Physics*, 121(21). <https://doi.org/10.1063/1.4984145>
12. Berkdemir, A., Gutiérrez, H. R., Botello-Méndez, A. R., Perea-López, N., Elias, A. L., Chia, C. I., Wang, B., Crespi, V. H., López-Urías, F., Charlier, J. C., Terrones, H., & Terrones, M. (2013). Identification of individual and few layers of WS<sub>2</sub> using Raman Spectroscopy. *Scientific Reports*, 3. <https://doi.org/10.1038/srep01755>
13. Zeng, H., Liu, G. bin, Dai, J., Yan, Y., Zhu, B., He, R., Xie, L., Xu, S., Chen, X., Yao, W., & Cui, X. (2013). Optical signature of symmetry variations and spin-valley coupling in atomically thin tungsten dichalcogenides. *Scientific Reports*, 3. <https://doi.org/10.1038/srep01608>
14. Ding, J., Feng, A., Li, X., Ding, S., Liu, L., & Ren, W. (2021). Properties, preparation, and application of tungsten disulfide: A review. In *Journal of Physics D: Applied Physics* (Vol. 54, Issue 17). <https://doi.org/10.1088/1361-6463/abd9e8>
15. Aji, A. S., Solís-Fernández, P., Ji, H. G., Fukuda, K., & Ago, H. (2017). High Mobility WS<sub>2</sub> Transistors Realized by Multilayer Graphene Electrodes and Application to High Responsivity Flexible Photodetectors. *Advanced Functional Materials*, 27(47). <https://doi.org/10.1002/adfm.201703448>
16. Rezaei nik, Y., Reyhani, A., Farjami-Shayesteh, S., & Mortazavi, S. Z. (2021). Photocurrent enhancement of hybrid perovskite CsGeBr<sub>3</sub> assisted two-dimensional WS<sub>2</sub> nano-flakes based on electron-hole mobility improvement. *Optical Materials*, 112. <https://doi.org/10.1016/j.optmat.2020.110754>
17. Huo, N., Kang, J., Wei, Z., Li, S. S., Li, J., & Wei, S. H. (2014). Novel and enhanced optoelectronic performances of multilayer MoS<sub>2</sub> -WS<sub>2</sub> heterostructure transistors. *Advanced Functional Materials*, 24(44). <https://doi.org/10.1002/adfm.201401504>
18. Higgins, T. M., Finn, S., Matthiesen, M., Grieger, S., Synnatschke, K., Brohmann, M., Rother, M., Backes, C., & Zaumseil, J. (2019). Electrolyte-Gated n-Type Transistors Produced from Aqueous Inks of WS<sub>2</sub> Nanosheets. *Advanced Functional Materials*, 29(4). <https://doi.org/10.1002/adfm.201804387>
19. Chen, J., Shao, K., Yang, W., Tang, W., Zhou, J., He, Q., Wu, Y., Zhang, C., Li, X., Yang, X., Wu, Z., & Kang, J. (2019). Synthesis of Wafer-Scale Monolayer WS<sub>2</sub> Crystals toward the Application in Integrated Electronic Devices. *ACS Applied Materials and Interfaces*, 11(21). <https://doi.org/10.1021/acsami.9b04791>
20. Kuc, A., Zibouche, N., & Heine, T. (2011). Influence of quantum confinement on the electronic structure of the transition metal sulfide TS<sub>2</sub>. *Physical Review B - Condensed Matter and Materials Physics*, 83(24). <https://doi.org/10.1103/PhysRevB.83.245213>



21. Tang, L. P., Tang, L. M., Geng, H., Yi, Y. P., Wei, Z., Chen, K. Q., & Deng, H. X. (2018). Tuning transport performance in two-dimensional metal-organic framework semiconductors: Role of the metal d band. *Applied Physics Letters*, *112*(1). <https://doi.org/10.1063/1.5000448>
22. Chung, Y. Y., Shieh, J. M., Su, S. K., Chiang, H. L., Chen, T. C., Li, L. J., Wong, H. S. P., Jian, W. bin, Chien, C. H., Lu, K. C., Cheng, C. C., Li, M. Y., Lin, C. T., Li, C. F., Chen, J. H., Lai, T. Y., & Li, K. S. (2019). Demonstration of 40-nm Channel Length Top-Gate p-MOSFET of WS<sub>2</sub> Channel Directly Grown on SiO<sub>x</sub>/Si Substrates Using Area-Selective CVD Technology. *IEEE Transactions on Electron Devices*, *66*(12). <https://doi.org/10.1109/TED.2019.2946101>
23. Tang, H., Shi, B., Pan, Y., Li, J., Zhang, X., Yan, J., Liu, S., Yang, J., Xu, L., Yang, J., Wu, M., & Lu, J. (2019). Schottky Contact in Monolayer WS<sub>2</sub> Field-Effect Transistors. *Advanced Theory and Simulations*, *2*(5). <https://doi.org/10.1002/adts.201900001>
24. Ernan-des, C., Khalil, L., Henck, H., Zhao, M. Q., Chaste, J., Oehler, F., Charlie Johnson, A. T., Asensio, M. C., Pierucci, D., Pala, M., Avila, J., & Ouerghi, A. (2021). Strain and spin-orbit coupling engineering in twisted ws<sub>2</sub>/graphene heterobilayer. *Nanomaterials*, *11*(11). <https://doi.org/10.3390/nano11112921>
25. Yang, B., Tu, M. F., Kim, J., Wu, Y., Wang, H., Alicea, J., Wu, R., Bockrath, M., & Shi, J. (2016). Tunable spin-orbit coupling and symmetry-protected edge states in graphene/WS<sub>2</sub>. *2D Materials*, *3*(3). <https://doi.org/10.1088/2053-1583/3/3/031012>
26. Tanoh, A. O. A., Alexander-Webber, J., Xiao, J., Delpo-rt, G., Williams, C. A., Bretscher, H., Gauriot, N., Allardice, J., Pandya, R., Fan, Y., Li, Z., Vignolini, S., Stranks, S. D., Hofmann, S., & Rao, A. (2019). Enhancing Photoluminescence and Mobilities in WS<sub>2</sub> Monolayers with Oleic Acid Ligands. *Nano Letters*, *19*(9). <https://doi.org/10.1021/acs.nanolett.9b02431>
27. Zhao, Y., & Jin, S. (2020). Controllable Water Vapor Assisted Chemical Vapor Transport Synthesis of WS<sub>2</sub>-MoS<sub>2</sub>Heterostructure. *ACS Materials Letters*, *2*(1). <https://doi.org/10.1021/acsmaterialslett.9b00415>
28. O'Brien, M., Lee, K., Morrish, R., Berner, N. C., McEvoy, N., Wolden, C. A., & Duesberg, G. S. (2014). Plasma assisted synthesis of WS<sub>2</sub> for gas sensing applications. *Chemical Physics Letters*, *615*. <https://doi.org/10.1016/j.cplett.2014.09.051>
29. Yousef Tizhoosh, N., Khataee, A., Hassandoost, R., DarvishiCheshmehSoltani, R., & Doustkhah, E. (2020). Ultrasound-engineered synthesis of WS<sub>2</sub>@CeO<sub>2</sub> heterostructure for sonocatalytic degradation of tylosin. *Ultrasonics Sonochemistry*, *67*. <https://doi.org/10.1016/j.ultsonch.2020.105114>
30. Leong, S. X., Mayorga-Martinez, C. C., Chia, X., Luxa, J., Sofer, Z., & Pumera, M. (2017). 2H → 1T Phase Change in Direct Synthesis of WS<sub>2</sub> Nanosheets via Solution-Based Electrochemical Exfoliation and Their Catalytic Properties. *ACS Applied Materials and Interfaces*, *9*(31). <https://doi.org/10.1021/acsami.7b06898>
31. Lan, C., Zhou, Z., Zhou, Z., Li, C., Shu, L., Shen, L., Li, D., Dong, R., Yip, S. P., & Ho, J. C. (2018). Wafer-scale synthesis of monolayer WS<sub>2</sub> for high-performance flexible photodetectors by enhanced chemical vapor deposition. *Nano Research*, *11*(6). <https://doi.org/10.1007/s12274-017-1941-4>
32. Mahler, B., Hoepfner, V., Liao, K., & Ozin, G. A. (2014). Colloidal synthesis of 1T-WS<sub>2</sub> and 2H-WS<sub>2</sub> nanosheets: Applications for photocatalytic hydrogen evolution. *Journal of the American Chemical Society*, *136*(40). <https://doi.org/10.1021/ja506261t>



33. Loh, T. A. J., Chua, D. H. C., & Wee, A. T. S. (2015). One-step Synthesis of Few-layer WS<sub>2</sub> by Pulsed Laser Deposition. *Scientific Reports*, 5. <https://doi.org/10.1038/srep18116>
34. Wang, S., Zhao, J., Yang, H., Wu, C., Hu, F., Chang, H., Li, G., Ma, D., Zou, D., & Huang, M. (2017). Bottom-up synthesis of WS<sub>2</sub> nanosheets with synchronous surface modification for imaging guided tumor regression. *Acta Biomaterialia*, 58. <https://doi.org/10.1016/j.actbio.2017.06.014>
35. Krishna, T. N. V., Himasree, P., Raghavendra, K. V. G., Rao, S. S., Kundakarla, N. B., Punnoose, D., & Kim, H. J. (2020). Hydrothermal synthesis of layered CoS@WS<sub>2</sub> nanocomposite as a potential electrode for high-performance supercapacitor applications. *Journal of Materials Science: Materials in Electronics*, 31(19). <https://doi.org/10.1007/s10854-020-04177-x>
36. Cheng, C. C., Chung, Y. Y., Li, U. Y., Lin, C. T., Li, C. F., Chen, J. H., Lai, T. Y., Li, K. S., Shieh, J. M., Su, S. K., Chiang, H. L., Chen, T. C., Li, L. J., Wong, H. S. P., & Chien, C. H. (2019). First demonstration of 40-nm channel length top-gate WS<sub>2</sub> pFET using channel area-selective CVD growth directly on SiO<sub>x</sub>/Si substrate. *Digest of Technical Papers - Symposium on VLSI Technology, 2019-June*. <https://doi.org/10.23919/VLSIT.2019.8776498>
37. Datta, K., Shadman, A., Rahman, E., & Khosru, Q. D. M. (2017). Trilayer TMDC Heterostructures for MOSFETs and Nanobiosensors. *Journal of Electronic Materials*, 46(2). <https://doi.org/10.1007/s11664-016-5078-0>
38. Sebastian, A., Pendurthi, R., Choudhury, T. H., Redwing, J. M., & Das, S. (2021). Benchmarking monolayer MoS<sub>2</sub> and WS<sub>2</sub> field-effect transistors. *Nature Communications*, 12(1). <https://doi.org/10.1038/s41467-020-20732-w>
39. Liu, M., Wei, S., Shahi, S., Jaiswal, H. N., Paletti, P., Fathipour, S., Remškar, M., Jiao, J., Hwang, W., Yao, F., & Li, H. (2020). Enhanced carrier transport by transition metal doping in WS<sub>2</sub> field effect transistors. *Nanoscale*, 12(33). <https://doi.org/10.1039/d0nr01573c>
40. Perea-López, N., Elías, A. L., Berkdemir, A., Castro-Beltran, A., Gutiérrez, H. R., Feng, S., Lv, R., Hayashi, T., López-Urías, F., Ghosh, S., Muchharla, B., Talapatra, S., Terrones, H., & Terrones, M. (2013). Photosensor device based on few-layered WS<sub>2</sub> films. *Advanced Functional Materials*, 23(44). <https://doi.org/10.1002/adfm.201300760>
41. Lan, C., Li, C., Ho, J. C., & Liu, Y. (2021). 2D WS<sub>2</sub>: From Vapor Phase Synthesis to Device Applications. In *Advanced Electronic Materials* (Vol. 7, Issue 7). Blackwell Publishing Ltd. <https://doi.org/10.1002/aelm.202000688>
42. Ma, X., Fu, S., Ding, J., Liu, M., Bian, A., Hong, F., Sun, J., Zhang, X., Yu, X., & He, D. (2021). Robust Interlayer Exciton in WS<sub>2</sub>/MoSe<sub>2</sub> van der Waals Heterostructure under High Pressure. *Nano Letters*, 21(19). <https://doi.org/10.1021/acs.nanolett.1c02281>
43. del Corro, E., Botello-Méndez, A., Gillet, Y., Elias, A. L., Terrones, H., Feng, S., Fantini, C., Rhodes, D., Pradhan, N., Balicas, L., Gonze, X., Charlier, J. C., Terrones, M., & Pimenta, M. A. (2016). Atypical Exciton-Phonon Interactions in WS<sub>2</sub> and WSe<sub>2</sub> Monolayers Revealed by Resonance Raman Spectroscopy. *Nano Letters*, 16(4). <https://doi.org/10.1021/acs.nanolett.5b05096>
44. Zhang, X., Qiao, X. F., Shi, W., Wu, J. bin, Jiang, D. S., & Tan, P. H. (2015). Phonon and Raman scattering of two-dimensional transition metal dichalcogenides from monolayer, multilayer to bulk material. In *Chemical Society Reviews* (Vol. 44, Issue 9). <https://doi.org/10.1039/c4cs00282b>



45. Kogo, G., Xiao, B., Danquah, S., Lee, H., Niyogushima, J., Yarbrough, K., Candadai, A., Marconnet, A., Pradhan, S. K., & Bahoura, M. (2020). A thin film efficient pn-junction thermoelectric device fabricated by self-align shadow mask. *Scientific Reports*, *10*(1). <https://doi.org/10.1038/s41598-020-57991-y>
46. Ding, L., Ukhtary, M. S., Chubarov, M., Choudhury, T. H., Zhang, F., Yang, R., Zhang, A., Fan, J. A., Terrones, M., Redwing, J. M., Yang, T., Li, M., Saito, R., & Huang, S. (2018). Understanding Interlayer Coupling in TMD-hBN Heterostructure by Raman Spectroscopy. *IEEE Transactions on Electron Devices*, *65*(10). <https://doi.org/10.1109/TED.2018.2847230>
47. Phan, N. A. N., Noh, H., Kim, J., Kim, Y., Kim, H., Whang, D., Aoki, N., Watanabe, K., Taniguchi, T., & Kim, G. H. (2022). Enhanced Performance of WS<sub>2</sub> Field-Effect Transistor through Mono and Bilayer h-BN Tunneling Contacts. *Small*, *18*(13). <https://doi.org/10.1002/sml.202105753>
48. Zhou, Y., Tan, H., Sheng, Y., Fan, Y., Xu, W., & Warner, J. H. (2018). Utilizing Interlayer Excitons in Bilayer WS<sub>2</sub> for Increased Photovoltaic Response in Ultrathin Graphene Vertical Cross-Bar Photodetecting Tunneling Transistors. *ACS Nano*, *12*(5). <https://doi.org/10.1021/acsnano.8b01263>
49. Mol, P. R., Barman, P. K., Sarma, P. v., Kumar, A. S., Sahu, S., Shaijumon, M. M., & Kini, R. N. (2021). Anomalously polarised emission from a MoS<sub>2</sub>/WS<sub>2</sub> heterostructure. *Nanoscale Advances*, *3*(19). <https://doi.org/10.1039/d1na00462j>
50. Hua, X., Zhang, D., Kim, B., Seo, D., Kang, K., Yang, E. H., Hu, J., Chen, X., Liang, H., Watanabe, K., Taniguchi, T., Hone, J., Kim, Y. D., & Herman, I. P. (2021). Stabilization of Chemical-Vapor-Deposition-Grown WS<sub>2</sub> Monolayers at Elevated Temperature with Hexagonal Boron Nitride Encapsulation. *ACS Applied Materials and Interfaces*, *13*(26). <https://doi.org/10.1021/acsaami.1c06348>
51. Tang, B., Yu, Z. G., Huang, L., Chai, J., Wong, S. L., Deng, J., Yang, W., Gong, H., Wang, S., Ang, K. W., Zhang, Y. W., & Chi, D. (2018). Direct n- to p-Type Channel Conversion in Monolayer/Few-Layer WS<sub>2</sub> Field-Effect Transistors by Atomic Nitrogen Treatment. *ACS Nano*, *12*(3). <https://doi.org/10.1021/acsnano.7b08261>
52. Schulman, D. S., Sebastian, A., Buzzell, D., Huang, Y. T., Arnold, A. J., & Das, S. (2017). Facile Electrochemical Synthesis of 2D Monolayers for High-Performance Thin-Film Transistors. *ACS Applied Materials and Interfaces*, *9*(51). <https://doi.org/10.1021/acsaami.7b14711>
53. Gong, Y., Carozo, V., Li, H., Terrones, M., & Jackson, T. N. (2016). High flex cycle testing of CVD monolayer WS<sub>2</sub> TFTs on thin flexible polyimide. *2D Materials*, *3*(2). <https://doi.org/10.1088/2053-1583/3/2/021008>
54. Britnell, L., Gorbachev, R. v., Jalil, R., Belle, B. D., Schedin, F., Mishchenko, A., Georgiou, T., Katsnelson, M. I., Eaves, L., Morozov, S. v., Peres, N. M. R., Leist, J., Geim, A. K., Novoselov, K. S., & Ponomarenko, L. A. (2012). Field-effect tunneling transistor based on vertical graphene heterostructures. *Science*, *335*(6071). <https://doi.org/10.1126/science.1218461>
55. Lu, Y., Chen, T., Mkhize, N., Chang, R. J., Sheng, Y., Holdway, P., Bhaskaran, H., & Warner, J. H. (2021). GaS:WS<sub>2</sub> Heterojunctions for Ultrathin Two-Dimensional Photodetectors with Large Linear Dynamic Range across Broad Wavelengths. *ACS Nano*, *15*(12). <https://doi.org/10.1021/acsnano.1c06587>



56. Nayak, P. K., Lin, F. C., Yeh, C. H., Huang, J. S., & Chiu, P. W. (2016). Robust room temperature valley polarization in monolayer and bilayer WS<sub>2</sub>. *Nanoscale*, 8(11). <https://doi.org/10.1039/c5nr08395h>
57. Hwang, W. S. *et al.* First demonstration of two-dimensional S<sub>2</sub> transistors exhibiting 10<sup>5</sup> room temperature modulation and ambipolar behavior. *Device Res. Conf. - Conf. Dig. DRC***013107**, 187–188 (2012).
58. Iqbal, M. W. *et al.* Tailoring the electrical and photo-electrical properties of a WS<sub>2</sub> field effect transistor by selective n-type chemical doping. *RSC Adv.***6**, 24675–24682 (2016).
59. Ott, S., Lakmann, M., & Backes, C. (2021). Impact of pretreatment of the bulk starting material on the efficiency of liquid phase exfoliation of WS<sub>2</sub>. *Nanomaterials*, 11(5). <https://doi.org/10.3390/nano11051072>
60. Wu, G., Sahoo, A. K., Chen, D. W. & Chang, J. W. A comparative study of e-beam deposited gate dielectrics on channelwidth-dependent performance and reliability of a-IGZO thin-film transistors. *Materials (Basel)*.**11**, (2018).
61. Illarionov, Y., Knobloch, T., & Grasser, T. (2021). (Invited) Where are the Best Insulators for 2D Field-Effect Transistors? *ECS Meeting Abstracts, MA2021-02*(12). <https://doi.org/10.1149/ma2021-0212609mtgabs>
62. Kumar, J., Kuroda, M. A., Bellus, M. Z., Han, S. J. & Chiu, H. Y. Full-range electrical characteristics of WS<sub>2</sub> transistors. *Appl. Phys. Lett.***106**, (2015).
63. Yang, A. *et al.* Giant Enhancement of Photoluminescence Emission in WS<sub>2</sub>-Two-Dimensional Perovskite Heterostructures. *Nano Lett.***19**, 4852–4860 (2019).
64. Hsiao, P. F., Anbazhagan, R., Tsai, H. C., Rajakumarikrishnamoorthi, Lin, S. J., Lin, S. Y., Lee, K. Y., Kao, C. Y., Chen, R. S., & Lai, J. Y. (2020). Fabrication of electroactive polypyrrole-tungsten disulfide nanocomposite for enhanced in vivo drug release in mice skin. *Materials Science and Engineering C*, 107. <https://doi.org/10.1016/j.msec.2019.110330>
65. Han, T., Liu, H., Chen, S., Chen, Y., Wang, S., & Li, Z. (2020). Fabrication and characterization of mos<sub>2</sub>/h-bn and ws<sub>2</sub>/h-bn heterostructures. *Micromachines*, 11(12). <https://doi.org/10.3390/mi11121114>
66. Li, C., Guo, J., Wang, C., Ma, D., & Wang, B. (2020). Design of MXene contacts for high-performance WS<sub>2</sub> transistors. *Applied Surface Science*, 527. <https://doi.org/10.1016/j.apsusc.2020.146701>
67. Khan, M. F., Ahmed, F., Rehman, S., Akhtar, I., Rehman, M. A., Shinde, P. A., Khan, K., Kim, D. K., Eom, J., Lipsanen, H., & Sun, Z. (2020). High performance complementary WS<sub>2</sub> devices with hybrid Gr/Ni contacts. *Nanoscale*, 12(41). <https://doi.org/10.1039/d0nr05737a>
68. Yang, Y., Li, H., Gu, Z., Chen, L., Zhu, H., Ji, L., & Sun, Q. (2021). Performance improvement in p-Type WS<sub>2</sub> field-effect transistors with 1T phase contacts. *Nanotechnology*, 32(34). <https://doi.org/10.1088/1361-6528/ac037d>
69. Zhang, Y., Zhang, Y., Ji, Q., Ju, J., Yuan, H., Shi, J., Gao, T., Ma, D., Liu, M., Chen, Y., Song, X., Hwang, H. Y., Cui, Y., & Liu, Z. (2013). Controlled growth of high-quality monolayer WS<sub>2</sub> layers on sapphire and imaging its grain boundary. *ACS Nano*, 7(10). <https://doi.org/10.1021/nn403454e>



70. Courtney, E., Conroy, M., & Bangert, U. (2020). Metal configurations on 2D materials investigated via atomic resolution HAADF stem. *Journal of Microscopy*, 279(3). <https://doi.org/10.1111/jmi.12902>
71. Jung, D. H., Oh, G. H., Kim, S. il, & Kim, T. (2022). Top-gate field-effect transistor based on monolayer WS<sub>2</sub> with an ion-gel gate dielectric. *Japanese Journal of Applied Physics*, 61(3). <https://doi.org/10.35848/1347-4065/ac4b6c>
72. Iqbal, M. W., Iqbal, M. Z., Khan, M. F., Shehzad, M. A., Seo, Y., Park, J. H., Hwang, C., & Eom, J. (2015). High-mobility and air-stable single-layer WS<sub>2</sub> field-effect transistors sandwiched between chemical vapor deposition-grown hexagonal BN films. *Scientific Reports*, 5. <https://doi.org/10.1038/srep10699>
73. Wang, J., Jia, R., Huang, Q., Pan, C., Zhu, J., Wang, H., Chen, C., Zhang, Y., Yang, Y., Song, H., Miao, F., & Huang, R. (2018). Vertical WS<sub>2</sub>/SnS<sub>2</sub> van der Waals Heterostructure for Tunneling Transistors. *Scientific Reports*, 8(1). <https://doi.org/10.1038/s41598-018-35661-4>
74. Mittal, P., Kumar, B., Negi, Y. S., Kaushik, B. K. & Singh, R. K. Channel length variation effect on performance parameters of organic field effect transistors. *Microelectronics J.* **43**, 985–994 (2012).
75. Abuzaid, H., Cheng, Z., Li, G., Cao, L., & Franklin, A. D. (2021). Unanticipated polarity shift in edge-contacted tungsten-based 2D transition metal dichalcogenide transistors. *IEEE Electron Device Letters*, 42(10). <https://doi.org/10.1109/LED.2021.3106286>
76. Yeh, C. H., Liang, Z. Y., Lin, Y. C., Ma, C. H., Chu, Y. H., Suenaga, K., & Chiu, P. W. (2020). Scalable T-Gate Aligned Gr-WS<sub>2</sub>-Gr Radio-Frequency Field-Effect Transistors. *ACS Applied Electronic Materials*, 2(12). <https://doi.org/10.1021/acsaelm.0c00742>